Electronic Supporting Information

Probing impact of interface mixing on charge carrier dynamics of a solution-processed organic light emitting diode via impedance spectroscopy

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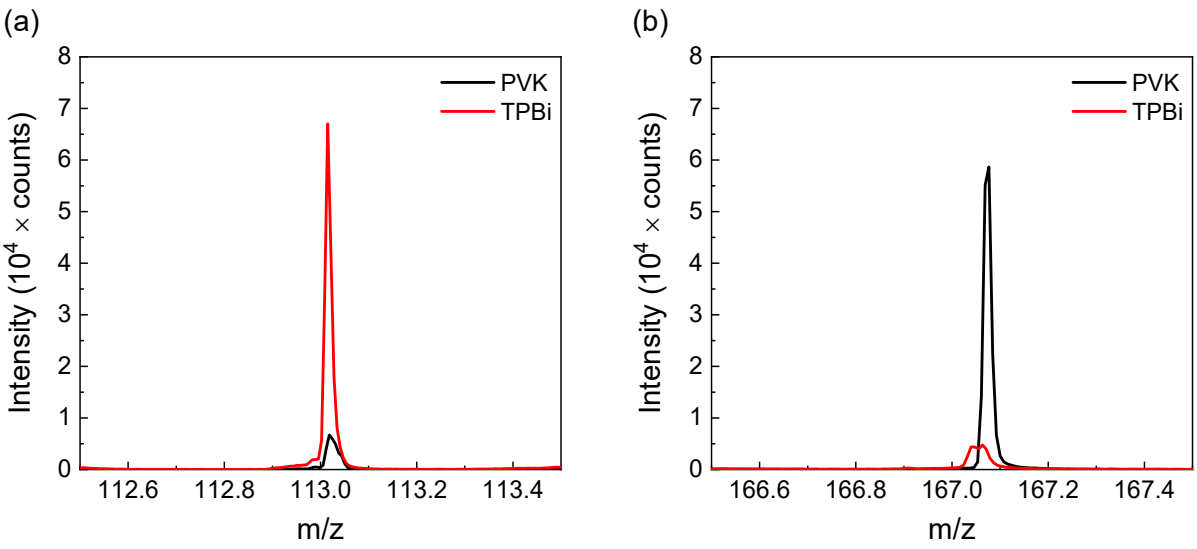

Fig. S1. Time-of-flight secondary ion mass spectrometry (ToF-SIMS) peaks of PVK (black) and TPBi (red) near **(a)** 113 and **(b)** 167 m/z.

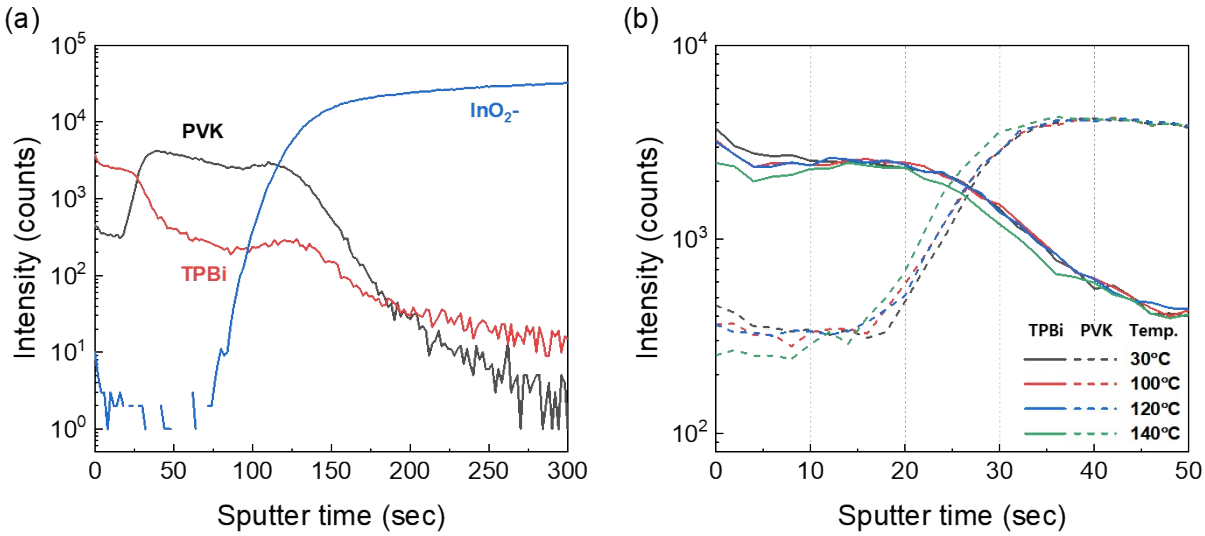

Fig. S2. (a) ToF-SIMS depth profiles of PVK (black), TPBi (red) and ITO (blue). **(b)** PVK (dashed line) and TPBi (solid line) depth profiles annealed at 30 (black), 100 (red), 120 (blue), and 140°C (green).